Abstracts

Characterization of asymmetric coupled CMOS lines

U. Arz, D.F. Williams, D.K. Walker, J.E. Rogers, M. Rudack, D. Treytnar and H. Grabinski. "Characterization of asymmetric coupled CMOS lines." 2000 MTT-S International Microwave Symposium Digest 00.2 (2000 Vol. II [MWSYM]): 609-612.

This paper investigates the properties of asymmetric coupled lines built in a 0.25 /spl mu/m CMOS technology in the frequency range of 50 MHz to 26.5 GHz. We show that the frequency-dependent line parameters extracted from calibrated four-port S-parameter measurements agree well with data predicted by numerical calculations. To our knowledge these are the first complete high-frequency measurements of the line parameters for asymmetric coupled lines on silicon ever reported.

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